Note: See data sheet for latest specifications. Values given in this application note are for reference only, and were considered correct at the time of publication (Feb. 1982).

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Designing Second-Generation Digital Telephony Systems Using the Intel 2913/14 Codec/Filter Combochip

Robert E. Holm
Telecom Technical Support

John Huggins
Telecom Design Engineering

1.0 INTRODUCTION

This application note describes the features and capabilities of the 2913 and 2914 codec/filter combochips, and relates these capabilities to the design and manufacturing of transmission and switching linecards.

1.1 Background

The first generation of per line codecs (Intel 2910A/11A) and filters (Intel 2912A) economically integrated the analog-digital conversion circuits and PCM formatting circuits into one chip and the filtering and gain setting circuits into another chip. These two chips helped to make possible the rapid conversion to digital switching systems that has taken place in the last few years.

The second generation of Intel LSI PCM telephony components, the 2913/14 Combochip, extends the level of integration of the linecard by combining the codec and filter functions for each line on a single LSI chip. In the process of combining both functions, circuit design improvements have also improved performance, reduced external component count, lowered power dissipation, increased reliability, added new features, and maintained architectural transparency.

The 2913 and 2914 data sheet contains a complete description of both parts, including detailed discussions of each feature and specifications for timing and performance levels. This application note, in conjunction with the data sheet, describes in more detail how the new and improved features help in the design of second-generation linecards first by comparing the two generations of components to see where the improvements have been made, and then by discussing specific design considerations.

1.2 Comparison of First- and Second-Generation Component Capabilities

The combochip represents a higher level of component integration than the devices it replaces and, because of the economics of LSI (replacing two chips with one), ultimately will cost significantly less at the component level. But comparison of the combochip block diagram with first-generation single-chip codec and filter reveals few major functional differences. Figure 1 compares the first-generation codec and filter chips to the combochip. Both provide rigidly specified PCM capabilities of voice signal bandlimiting and nonlinear companded A/D and D/A conversion. The first on-chip reference voltage was introduced in the 2910/2911 single-chip codecs and is included in the combochip. The provision of uncommitted buffer amplifiers for flexible transmission level adjustment and enhanced analog output drive was a feature of the now standard 2912 switched-capacitor PCM filter is available on the combochip. Likewise, independent transmit (A/D) and receive (D/A) analog voice channels which permit the two channels to be timed from independent (asynchronous) clock sources is common to the first- and second-generation devices. Finally, the ability to multiplex signalling bits on a bit-stealing basis from the digital side of the device has been duplicated on the combochip.

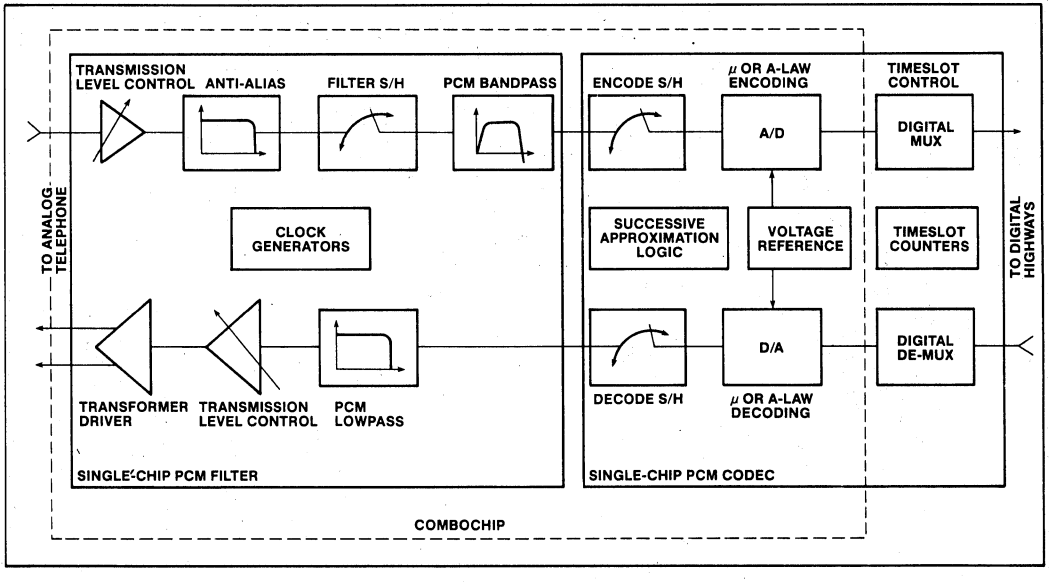


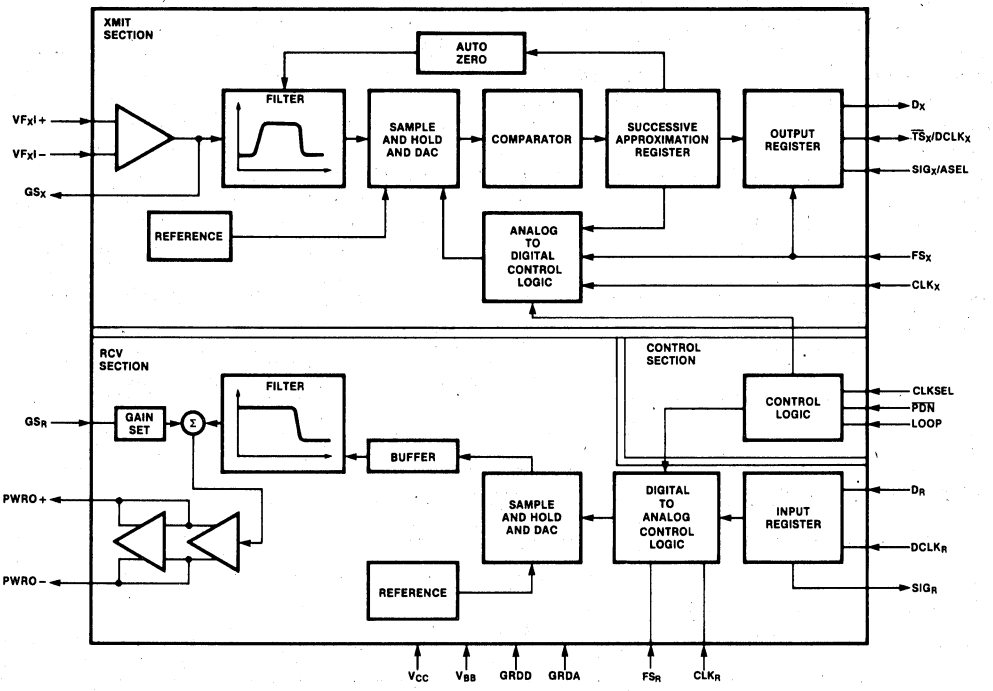
Figure 1. LSI Partitioning of Codec/Filter Functions

Data traffic-conscious systems manufacturers now provide dedicated codec, filter, and subscriber interface functions on a per-subscriber basis, which in turn puts intense cost pressures on these functions. The functional duplication of first-generation components addresses the needs of the system manufacturer who wants to cost reduce existing fixed-architecture system designs. Whereas the bulk of the system development costs (and time) are in the switching machine call processing and diagnostic software, the bulk of the production costs are in the high-volume linecards. The combochip addresses these cost pressures and defers the appetite for new integrated functions to a future generation of PCM components.

Figure 2 contains the block diagram of the 2913/14 combochip which illustrates not only the basic companding and filtering functions but also some of the changes and new features contained in the second-generation devices, such as internal auto zero, separate ADC and DAC for transmit and receive sections, respectively, precision gain setting (RCV section), and input/output registers for both fixed and variable data rates. Table 1 lists many of the features that are important to linecard design and performance. A direct comparison between first- and second-

Table 1. Comparison between 2913/14 Combochip and the 2910A/11A/12A Single-Chip Codecs and Filters

Features	2910A/11A plus 2912A	2913/14
Power — Operating	280–310 mW	140 mW
Power — Standby	33 mW	5 mW
Pins	38–40	20–24
Board Area Including Interconnects	Normalized = 1.0	0.33
Data Rates — Fixed	1.536, 1.544, 2.048 Mbps	Same
Data Rates — Variable	None	64 Kbps → 2.048 Mbps
Companding Law — μ-Law	2910 + 2912	Strap Selectable
Companding Law — A-Law	2911 + 2912	
PSRR — 1 kHz	30 dB	> 35 dB
PSRR — > 10 kHz	Not Spec'd	> 35 dB
Gain Setting	Trim Using Pot Necessary	Precision Resistors Eliminate Trim Req.
Operating Modes — Direct	yes	yes
Operating Modes — Timeslot Assign	yes	no
On-Chip Vref	yes	yes
ICN — half channel improvement	15 dBrncO Transmit 11 dBrncO Receive	15 dBrncO Transmit 11 dBrncO Receive
S/D — half channel improvement	See Data Sheet	See Section 2.0
GT — half channel improvement	See Data Sheet	See Section 2.0
Power Down (Standby)	PDN Pin	Frame Sync Removal or PDN Pin
Signalling	2910-8th Bit	2914-8th Bit
Auto Zero	External	Internal
S & H Caps	External Transmit Internal Receive	Internal
Test Modes	None	Design Tests Manufacturing Test On-Line Operational Tests
Encoder Implementation	Resistive Ladder	Capacitive Charge Redistribution Ladder
Filter/Gain Trim	Fuse Blowing ±0.2 dB	Fuse Blowing ±0.04 dB



(a) Combochip Block Diagram

V_{BB}	Power (-5V)	GS_X	Transmit Gain Control
PWRO+, PWRO−	Power Amplifier Outputs	VF_XI-, VF_XI+	Analog Inputs
GS_R	Receive Gain Control	GRDA	Analog Ground
$\overline{PDN}$	Power Down Select	NC	No Connect
CLKSEL	Master Clock Frequency Select	SIG_X	Transmit Signaling Input
LOOP	Analog Loop Back	ASEL	μ- or A-law Select
SIG_R	Receive Signaling Bit Output	$\overline{TS}_X$	Timeslot Strobe/Buffer Enable
$DCLK_R$	Receive Variable Data Clock	$DCLK_X$	Transmit Variable Data Clock
D_R	Receive PCM Input	D_X	Transmit PCM Output
FS_R	Receive Frame Synchronization Clock	FS_X	Transmit Frame Synchronization Clock
GRDD	Digital Ground	CLK_X	Transmit Master Clock
V_{CC}	Power (+5V)	CLK_R	Receive Master Clock

(b) Combochip Pin Names

Figure 2. Block Diagram of 2913/14 Combochip

generation products shows the significant improvement in the combochip both in performance levels and system flexibility.

2.0 DESIGN CONSIDERATIONS

The key point with the 2913/14 is that it will result in a linecard that performs better and costs less than any two-chip codec/filter solution. The lower cost results from many factors, as seen in Table 2. Both direct replacement costs and less tangible design and manufacturing time savings combine to yield lower recurring and nonrecurring costs. As an example, the wider margins to transmission specs and the higher power supply rejection ratios of the 2913/14 will both shorten the design time needed to build and test the linecard prototype and reduce the reject rate on the manufacturing line.

Table 2. 2913/14 Factors which Lower the Cost of Linecard Design and Manufacturing

- Lower LSI Cost (2914 vs. 2910/11 + 2912)
- Fewer External Components
- Less Board Area
- Shorter Design/Prototype Cycle
- Better Yields/Higher Reliability
- Lower Power/Higher Density

Part of the recurring cost of linecard production is the efficiency of the manufacturing line in turning out each board. This is measured in both parts cost and time. Average manufacturing time is strongly effected by the line yield, i.e., the reject rate reliability. A linecard using the 2913/14 has many labor-saving features, which also increases the *reliability* of the manufacturing process. Some of these features are detailed in Table 3.

The combination of fewer parameters to trim (gain, reference voltage, etc.), tolerance to wider power supply variations, and on-chip test modes make the linecard very manufacturable compared to first-generation designs.

Probably the most obvious improvement in linecard design based around the 2913/14 is the reduction in linecard PCB area needed compared to two-chip designs. The combination of the codec and filter into a single package alone reduced the LSI area by one-third. Table 4 shows many of the other ways in which board area is conserved. In general, it reduces to fewer components, more on-chip features, and layout of the chip resulting in an efficient board layout which neatly separates the analog and digital signals both inside the chip and on the board.

Table 3. 2914 Factors which Increase Linecard Manufacturing Yields and Efficiency

- Higher Reliability
  - —Fewer connections & components
  - —more integrated packaging
  - —more margin to specs
  - —lower power
  - —NMOS proven process
  - —Less sensitive to parameter variations
- Fewer Manufacturing Steps
  - —no gain trimming
  - —on chip Vref
  - —wide power supply tolerance
  - —on chip test modes
  - —wide margins to specs

Table 4. Design Factors for 2914 which Reduce Linecard PCB Area

- Integrated Packaging
  - —2914 vs. 2910/11 + 2912 = 1/3 board area
  - —2913 takes even less space
- Fewer Interconnects/Components
  - —codec/filter combined
  - —on-chip reference voltage
  - —on-chip auto zero
  - —on-chip capacitors
  - —no gain trim components
  - —no voltage regulators
- Efficient Layout (Facilitates Auto Insertion,
  - —analog/digital sections separated on chip
  - —digital traces can cross under chip
  - —two power supplies only
  - —low power/high density

Table 5. 2913/14 Operating Mode Options Add Flexibility to Linecard Design

Option	Mode Control Pins	Results of Mode Selection	
		2914 (24 pin)	2913 (20 pin)
Companding Law	SIGX/ASEL	A-Law or μ-Law + Signalling	A-Law/μ-Law, no Signalling
Power Down	$\overline{PDN}$	Transmit & Receive Side Go To Standby Power (5 mW)	
	FS_X & FS_R Removed	Same (12 mW)	
	FS_X Removed	Transmit Side Goes to Standby (110 mW)	
	FS_R Removed	Receive Side Goes to Standby (70 mW)	
Data Rate	= V_{CC}/GRDD/V_{BB} $DCLK_R$ = V_{BB}	1.536/1.544/2.048 Mbps in fixed data rate mode	
	= V_{CC}/GRDD/V_{BB} $DCLK_R$ = Clock	Variable Data Rate Mode from 64 Kbps to 2.048 Mbps, No Signalling	
Test Modes	LOOP = V_{CC}	Implements Analog Loopback	No Loopback Capability
	$\overline{PDN}$ = V_{BB}	Provides Access to Transmit Codec Through ASEL and $\overline{TSX}$ Pins	
	D_R = V_{BB}	Provides Access to RCV Filter Input at $DCLK_R$ and Transmit Filter Outputs at ASEL and $\overline{TSX}$ Pins	

Many of the factors discussed above—which result in efficient, cost-effective linecard designs—are discussed in more detail both in the 2913/14 data sheet and in the following sections of this note.

2.1 Operating and Test Mode Selection

A key to designing with the 2913/14 combo is the wide range of options available in configuring, either with strap options or in real time, the different modes of operation. The 2913 combochip (20 pins) is specifically aimed at synchronous switching systems (remote concentrators, PABXs, central offices) where small package size is especially desirable. The 2914 combochip (24 pins) has additional features which are most suitable for applications requiring 8th-bit signalling, asynchronous operation, and remote testing of transmission paths (e.g., channel banks). Once the specific device is selected, there is a wide range of operating modes to use in the card design, as seen in Table 5. This table lists the optional parameters and the pins which control the operating mode. The result of selecting a mode is listed for both the 2913 and 2914.

The purpose of offering these options is to ensure that the 2913/14 combo will accommodate any existing linecard design with architectural transparency. At the same time, features were designed in to facilitate design and manufacturing testing to reduce overall cost of development and production.

2.2 Data Rate Modes

Any rapid conversion scenario presumes that the combochip will fit existing system architectures (retrofit) without significant system timing, control, or software modifications. To this end, two distinct user-selectable timing modes are possible with the combochip. For purposes of discussion, these are designated (a) fixed data rate timing (FDRT) and (b) variable data rate timing (VDRT).

FDRT is identical to the 2910/2911 codec timing in which a single high-speed clock serves both as master clock for the codec/filter internal conversion/filtering functions and as PCM bit clock for the high-speed serial PCM data bus over which the combochip transmits and receives its digitized voice code words. In this mode, PCM bit rates are necessarily confined to one of three distinct frequencies (1.536 MHz, 1.544 MHz, or 2.048 MHz). Many recently designed systems employ this type of timing which is sometimes referred to as burst-mode timing because of the low duty cycle of each timeslot (i.e., channel) on the time division multiplexed PCM bus. It is possible for up to 32 active combochips to share the same serial PCM bus with FDRT.

VDRT (sometimes referred to as shift register timing), by comparison, utilizes one high-speed master clock for the combochip internal conversion/filtering functions and a separate, variable frequency, clock as the PCM bit clock for the serial PCM data bus. Because the serial PCM data rate is independent of internal conversion timing, there is considerable flexibility in the choice of PCM data rate. In this mode the master clock is permitted to be 1.536 MHz, 1.544 MHz, or 2.048 MHz, while the bit clock can be any rate between 64 kHz and 2.048 MHz. In this mode it is possible to have a dedicated serial bus for each combochip or to share a single serial PCM bus among as many as 32 active combochips.

Thus, the two predominant timing configurations of pres-

ent system architectures are served by the same device, allowing, in many cases, linecard redesign without modification of any common system hardware or software. Additional details relating to the design of systems using either mode are found in section 3.0.

2.3 Margin to Performance Specifications

The combochip benefits from design, manufacturing, and test experience with first-generation PCM products on the part of the system manufacturer, component suppliers, and test equipment suppliers. The sub-millivolt PCM measurement levels and tens of microvolts accuracy requirements on the lowest signal measurements often result in tester correlation problems, yield losses, and excess costs for system and PCM component manufacturers alike. Thus additional performance margin built into the PCM components themselves will have its effect on line circuit costs even though the system transmission specifications may not reflect the improved performance margin.

Half channel measurements have been made of the transmission parameters—gain tracking (GT), signal to distortion ratio (S/D), and idle channel noise (ICN).

Gain Tracking—Figure 3 shows the gain tracking data for both the transmit and receive sides of the combo using both sine wave testing (CCITT G712.11 Method 2) and white noise testing (CCITT G712.11 Method 1). The data shows a performance very nearly equal to the theoretically best achievable using both test techniques. End to end measurements, although not spec'd, also show a corresponding good performance with errors less than or equal to the sum of the half channel values.

Signal to Distortion Ratio—This is a measure of the system linearity and the accuracy in implementing the companding codes. Figure 4 shows the excellent perfor-

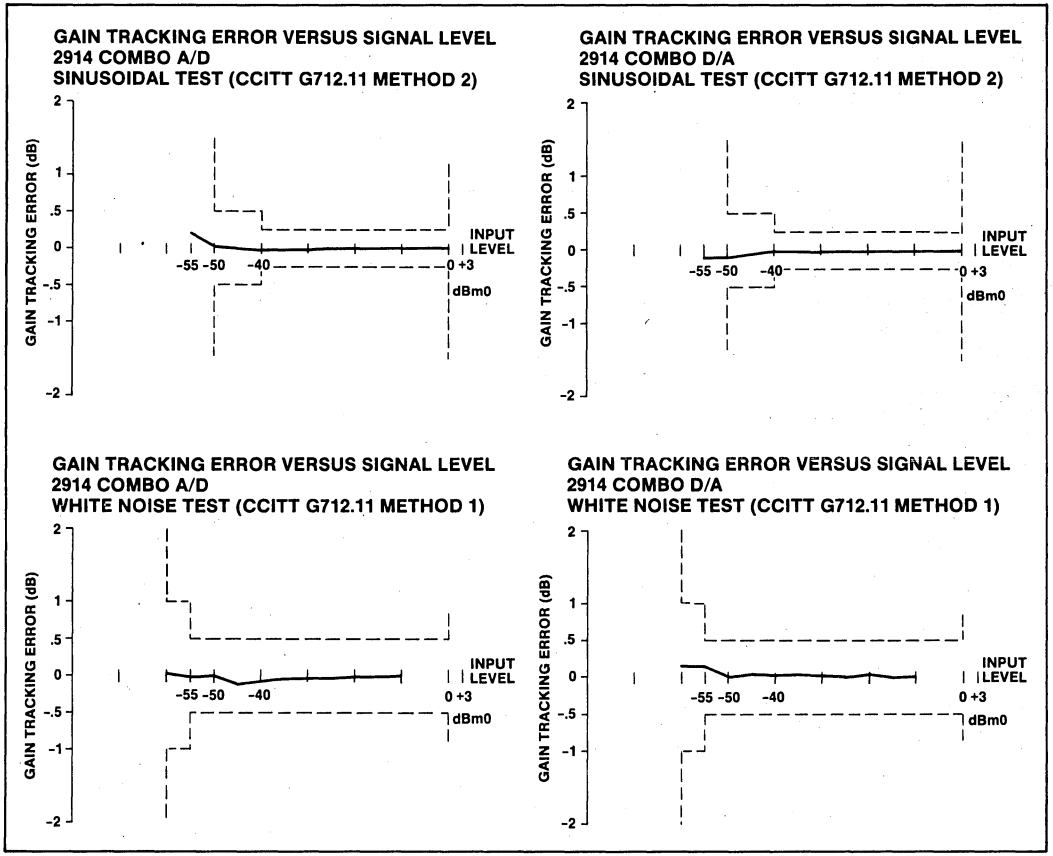


Figure 3. 2914 Half Channel Gain Tracking Performance Measurements for both Sine and Noise Testing

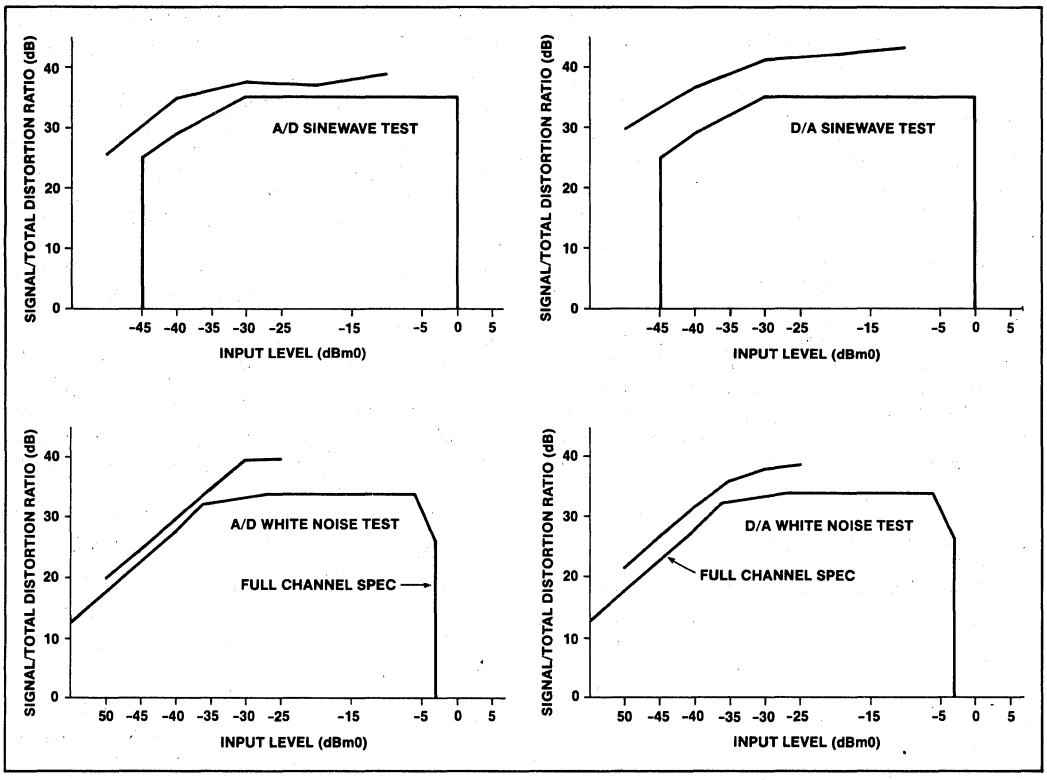


Figure 4. 2914 Half Channel Signal to Distortion Ratio (S/D) Performance Measurements for both Sine and Noise Testing

mance of the 2914 for both the transmit (A/D) and receive (D/A) channels using sine wave and noise testing. The margin is greater than 3 dB above the half channel spec which means that a larger error budget is available to the rest of the channel.

Statistical Analysis—A statistical analysis of G.T. and S/D measurements over many devices shows a very tight distribution, as seen in Figure 5. There are several consequences resulting from this highly desirable distribution: (1) the device performance is controllable, resulting in high yields, (2) the device circuit design is tolerant of normal process variations, thereby ensuring predictable production yields and high reliability, and (3) understanding of the circuit design and process fundamentals is clearly demonstrated—largely as a result of previous telephony experience with the Intel NMOS process.

Idle Channel Noise—The third transmission parameter is idle channel noise (ICN). Figure 6 gives half channel ICN measurements which show a substantial margin to specification.

Power Supply Rejection—Circuit innovation in the internal combochip design has resulted in significant improvements in power supply rejection in the 5 to 50 kHz range (Figure 7), and it is this frequency band which usually contains the bulk of the switching regulator noise. These higher frequencies, outside the audio range as they are, are not objectionable or even detectable in the transmit direction except to the extent that they alias into the audio range as a result of internal sampling processes in the transmit filter and A/D converter. Sampling techniques in the combochip minimize this aliasing. In the receive direction, excess high frequency noise which propagates onto the subscriber loop can interfere with signals in adjacent wires and is thus objectionable even without aliasing. The symmetrical true differential analog outputs of the combochip are an improvement from earlier designs which failed to maintain true power supply symmetry through the output amplifiers. Not only does the differential design improve transmission performance, but it also reduces the need for power supply bypass capacitors, thereby saving component cost on the linecard.

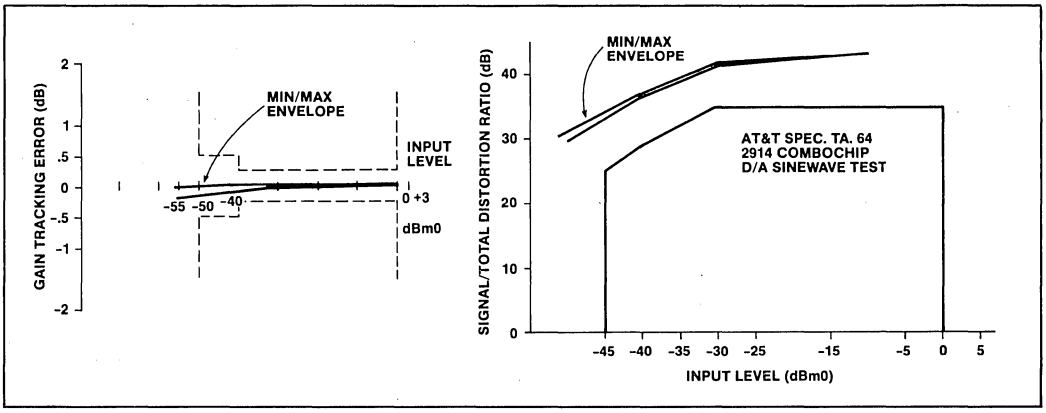


Figure 5. Statistical Analysis of Transmission Performance Showing Tight Distribution over many Devices

	WEIGHTING	ICN
A/D	C MESSAGE	15 dBrnCO
D/A	C MESSAGE	11 dBrnCO

Figure 6. 2914 Idle Channel Noise (ICN) Measurements

Autozero—The autozero circuit is contained completely on-chip. It automatically centers the signal/noise distribution at the encoder input. This ensures minimal ICN due to bit toggeling and also maintains maximum sensitivity to the AC signals of interest.

2.4 Power Conservation

Figure 8 illustrates typical power consumption and office equipment dissipation for a resistive line biasing arrangement (with no loop current limiting) and for the per-line PCM components. It can be seen that overall line circuit power consumption and dissipation are strong functions of subscriber loop resistance, and are dominated by line biasing current regardless of loop length. It can also be seen that the combochip achieves significant reductions in PCM component contributions relative to both the 2910A/2912A and 2910/2912. Present residential traffic characteristics are such that the PCM components are active less than 10% of the time, and in its low-power standby state, the combochip power dissipation drops to typically 5 mW as the line current (and dissipation) goes to its background on-hook leakage level of typically a few milliwatts (but for very leaky lines, as much as 50–500 mW).

The concern for linecard power consumption and dissipation is related both to the cost of providing power and to the system density problem involving convection heat removal from the linecards. Consequently, much recent line circuit development activity centers on elimination of the inefficient resistive line current feed both by current limiting in short loops and by more exotic and expensive per-line dc-dc converters. For both present-generation designs and cost-reduction redesigns, the typical combochip dissipation of 140 mW active/5 mW standby will allow system board packing density improvements and power supply cost reductions.

A closer look at the effect of loading (duty cycle) on the average power dissipation of a combochip is given in Table 6. Typical loading percents run as low as 5% for very large switching systems (thousands of lines) up to

Table 6. Typical Power Dissipation Per Line Using 2914 Combochip

	Duty Cycle	Power Dissipation
Central Office	5%	12 mW
PABX	15%	25 mW
Peak Hour C.O.	50%	73 mW
Channel Bank	100%	140 mW

100% in nonswitching applications such as channel banks. Clearly, the average power dissipation in a typical switching system is below 35 mW which facilitates board packing density and cost of power considerations.

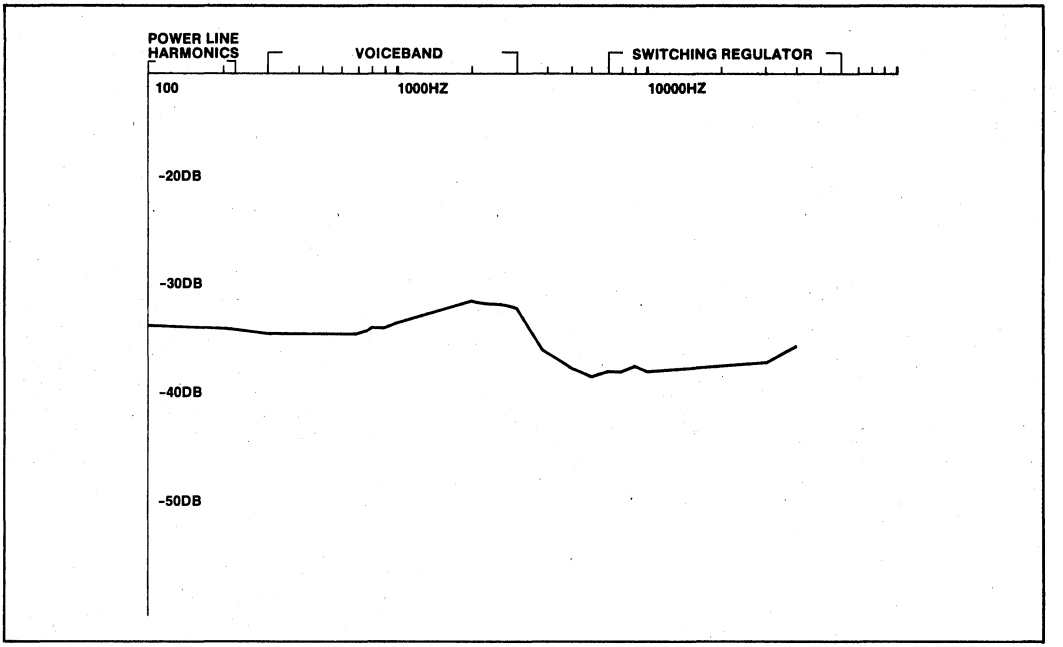


Figure 7. Wideband 2914 Power Supply Rejection Ratio (PSRR)

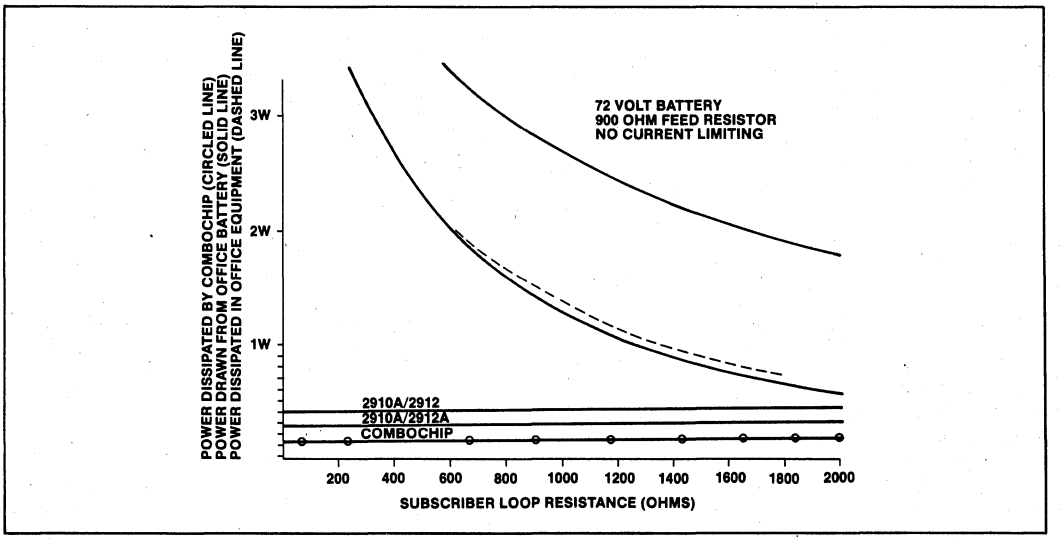


Figure 8. Line Circuit Power Consumption and Dissipation Curves

2.5 Elimination of Gain Trim in the Line Circuit

Four resistors—R1-R4 of Figure 9—on the transformer side of the PCM components are used to establish appropriate transmission levels at the PCM components and are, at first glance, equivalent in the two cases. However, a significant reduction in linecard manufacturing costs associated with individual line trim (or mop-up) is possible with the combochip. The need for this trim is dictated by system gain contrast specifications which typically require that the line-to-line gain variation shall not exceed 0.5 dB, which translates to 0.25 dB for each (transmit and receive) channel. Table 7 shows that the major portion of this gain variation has previously been in the nominal insertion loss of the PCM filter and in the uncertainty of the reference voltage of the codec. With this cumulative 0.15 dB uncertainty in the PCM components themselves, the system manufacturer had no choice but to resort to the cost and manufacturing complexity of the active trim. The combochip, however, can be trimmed during its manufacture to a nominal tolerance of ±0.04 dB which includes uncertainties in both the filter and codec voltage reference functions. This leaves 0.21 dB uncertainty to variations in the other line circuit elements and to temperature and supply variations.

The variation in combochip gain with supply and temperature has also been improved to allow as low as

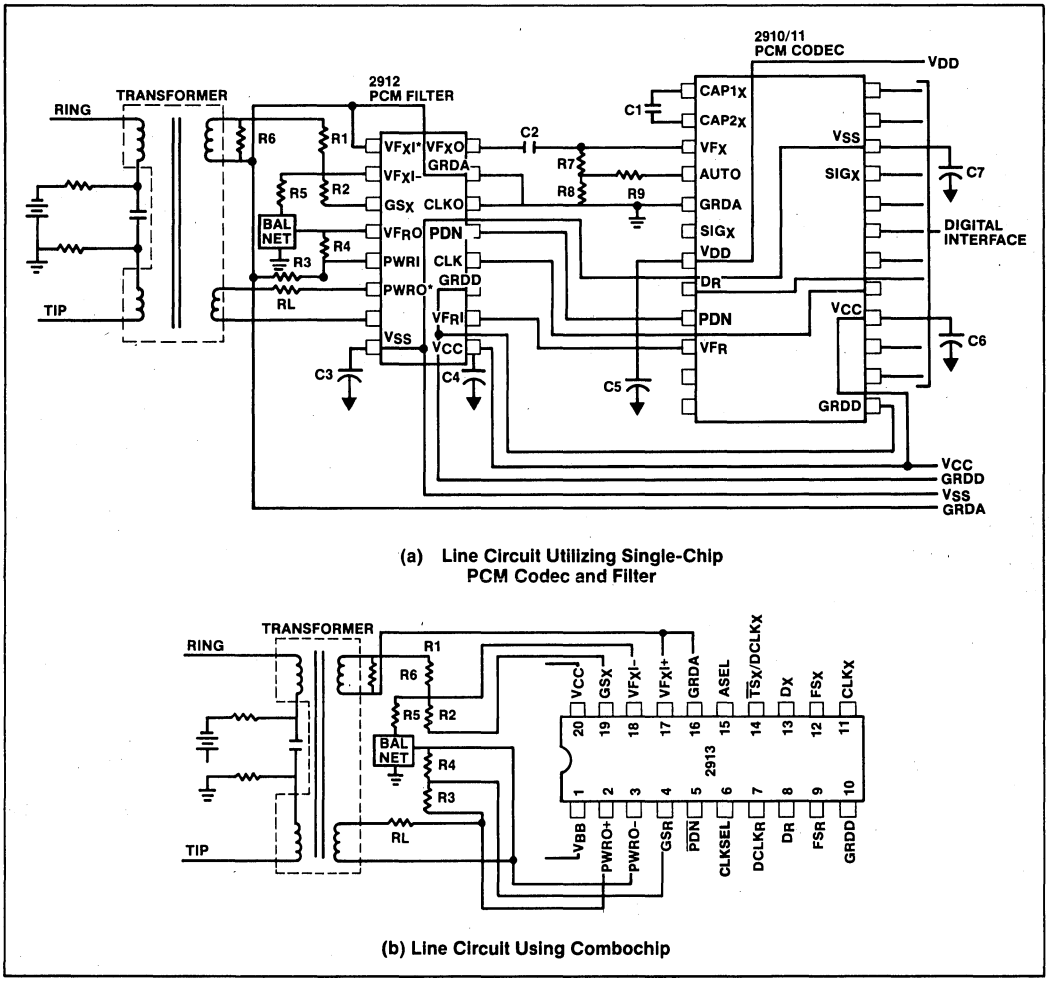


Figure 9. Schematics of the Codec/Filter Function and the 2/4 Wire Hybrid Transformers

Table 7. Gain Trim Budget for Codec/Filter Functions

Device	Manufacturing Uncertainty (Initial)	ΔT Δ Supplies	Total	Variation* Budget for Other Components
2910 2912	±0.1 ±0.05	±0.1 ±0.05		
	±0.15	±0.15	±0.3 dB	0 dB
2914	±0.04	±0.08	±0.12 dB	±0.13 dB

*Assumes 0.5 dB end to end gain contrast specification.

0.08 dB variation over supplies and temperature so that more than half the system specification could be reserved for transformer, wiring, and resistor uncertainties. This possibility of using fixed precision gain trim components and abandoning the active trim holds the potential for simplification and cost reduction of the line board manufacturing process.

2.6 Power Up/Down Considerations

Power Supply Sequence—There are no requirements for a particular sequence of powering up the combochip. All discussions of power up or power down timing assume that both V_{CC} and V_{BB} are present.

Power Up Delay—Upon application of power supplies, or coming out of the standby power down mode, three circuit time constants must be observed: (1) digital signal timing, (2) autozero timing, and (3) filter settling. An internal timing circuit activates SIG_r, D_X, and TS_X approximately two to three frames after power up. Until this time, SIG_r is held low and the other two signals are in a tri-state mode. During this time, SIG_X will have no effect on the PCM output.

Power Down Modes—These modes are described in detail in Table 3 of the 2913/14 data sheet except for a fail-safe mode in case CLK_X is interrupted. If this should happen, both D_X and TS_X go into the tri-state mode until the clock is restored. This ensures the safety of the PCM highway should the interrupted clock be a local problem.

3.0 OPERATING MODES

There are three basic operating modes that are supported by the 2913/14: fixed data rate timing (FDRT), variable data rate timing (VDRT), and on-line testing.

3.1 Fixed Data Rate Mode

The FDRT mode is described in some detail in both section 2.2 of this note and in the 2913/14 data sheet. In addition, Intel Application Note AP-64 (Data Conversion, Switching, and Transmission using the Intel 2910A/2911A codec and 2912 PCM filter) also describes the basics of using the fixed data rate mode for first-generation codecs and filters which is essentially the same as for the 2913/14 second-generation combochip.

3.2 Variable Data Rate Mode

The VDRT mode is described in some detail both in section 2.2 and in the 2913/14 data sheet. This section focuses on two design aspects: (1) the advantage of clocking data on the rising and falling edges of the clock for transmit and receive data, respectively, and (2) making the 2913/14 transparent in previously designed systems (a retrofit, cost reduction redesign).

Clock Timing—The 2913/14 is ideally set up to transmit and receive data, using the same clock, with no race conditions or other marginal timing requirements. This is accomplished by transmitting data on the rising edge of the first clock pulse following the data enable pulse FS_X and receiving data on the falling edge of the clock which is directly in the middle of the D_X data pulse. Several manufacturers use leading edge timing for both transmit and receive requiring an inversion of the receive clock.

Figure 10 shows the transmit and receive clock and data timing for an entire time slot of data. A closer look at the timing functions is given in Figure 11 which looks specifically at the first clock cycle after the transmit data enable FS_X.

According to the 2913/14 data sheet, the frame sync/data enable FS_X must precede the clock ($DCLK_X$) by at least T_{tsdx} or nominally 15 nsec for that clock pulse to be recognized as the first clock pulse in the time slot. In actuality, the 2914 will allow FS_X to lag up to 80 nsec the $DCLK_X$ rising edge and recognize it as the first clock pulse in a 2.048 MHz system.

Once FS_X has reached V_{IH} of about 2 volts, the D_X output will remain in the tri-state high-impedance mode for

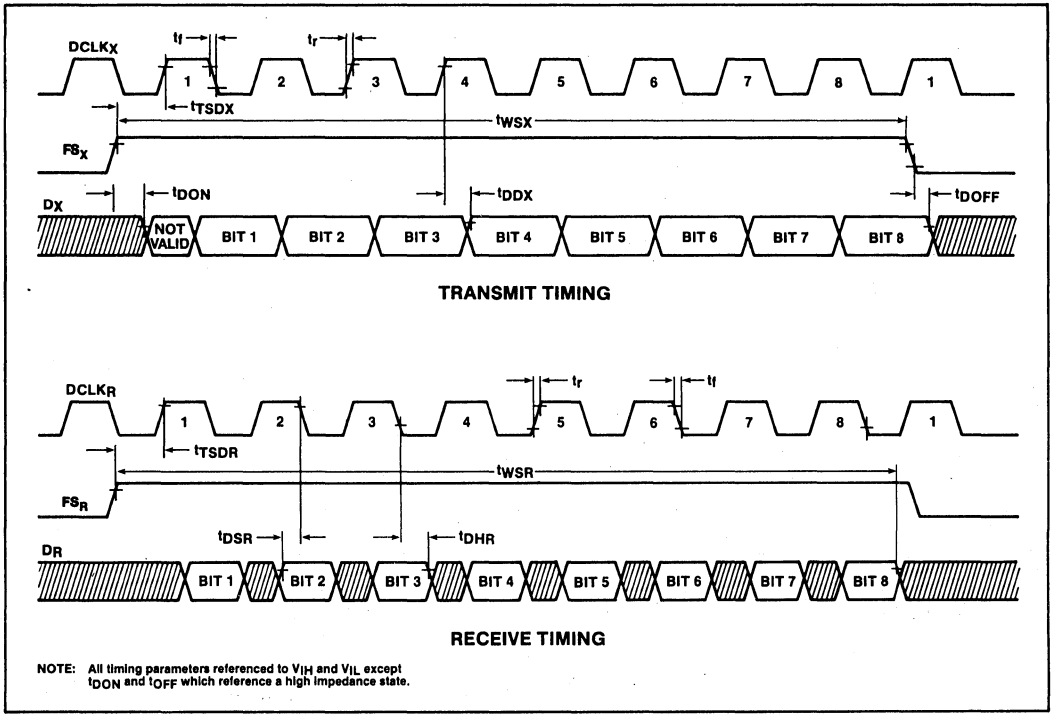


Figure 10. Variable Data Rate Timing for an Entire Time Slot

T_{don} or about 35 nsec longer. It then comes out of tri-state and will represent some data which is invalid until the valid data is available T_{DDX} or about 75 nsec (100 nsec worst case) after the clock rising edge. This means there is about 90 nsec of invalid data after the tri-state mode. At this point there is valid data on the D_X highway that lasts for approximately one full clock cycle.

Since the D_X highway is tied directly to the D_r highway in digital loopback, the valid data above is now available to the receive channel with some propagation delay. The receiver is only interested in the data for about a 50 nsec (110 nsec worst case) window centered about the falling edge of the $DCLK_r$ clock which occurs about half a clock cycle from the FS_r rising edge. The window width is equal to the data set-up time. T_{dsr}, plus the clock fall time, T_f, plus the data hold time, T_{dhr}. Information at any other time on the D_r highway falls into the DON'T CARE category.

Retrofitting the 2913/14—Several switching/transmission systems have been designed using first-generation codecs which operate at data rates from 64 Kbps to 2.048 Mbps. In addition, they may have been designed using the rising clock edges for both transmit and receive data. Other aspects of these older designs could be relative skewing between the sync pulses (Data Enable) and the clock pulses in such a way that the sync pulse occurs after (Lags) the first clock pulse rising edge. All of these conditions can be easily handled using the variable data rate timing mode of the 2913/14 plus some simple external logic. By the addition of this logic, the 2913/14 becomes transparent to the older design thereby allowing an upgrade in performance while having no impact on backplane wiring or on system control hardware/software. In addition, many of the features of the 2913/14 may be incorporated, such as the test modes, which provide additional capabilities beyond those available in the original design and at a lower cost.

The circuit diagram in Figure 12 shows the maximum amount of additional random logic that could be necessary to make the 2913 or 2914 completely transparent at the linecard level (no impact on backplane wiring or timing). The inverter on $DCLK_R$ inverts all the receive clocks for each linecard. This inverter is only needed if (1) the transmit and receive clocks are inverted at the system/backplane level (as opposed to the linecard level) and (2) the previous design used only rising (or falling) edges to clock the transmit/receive data.

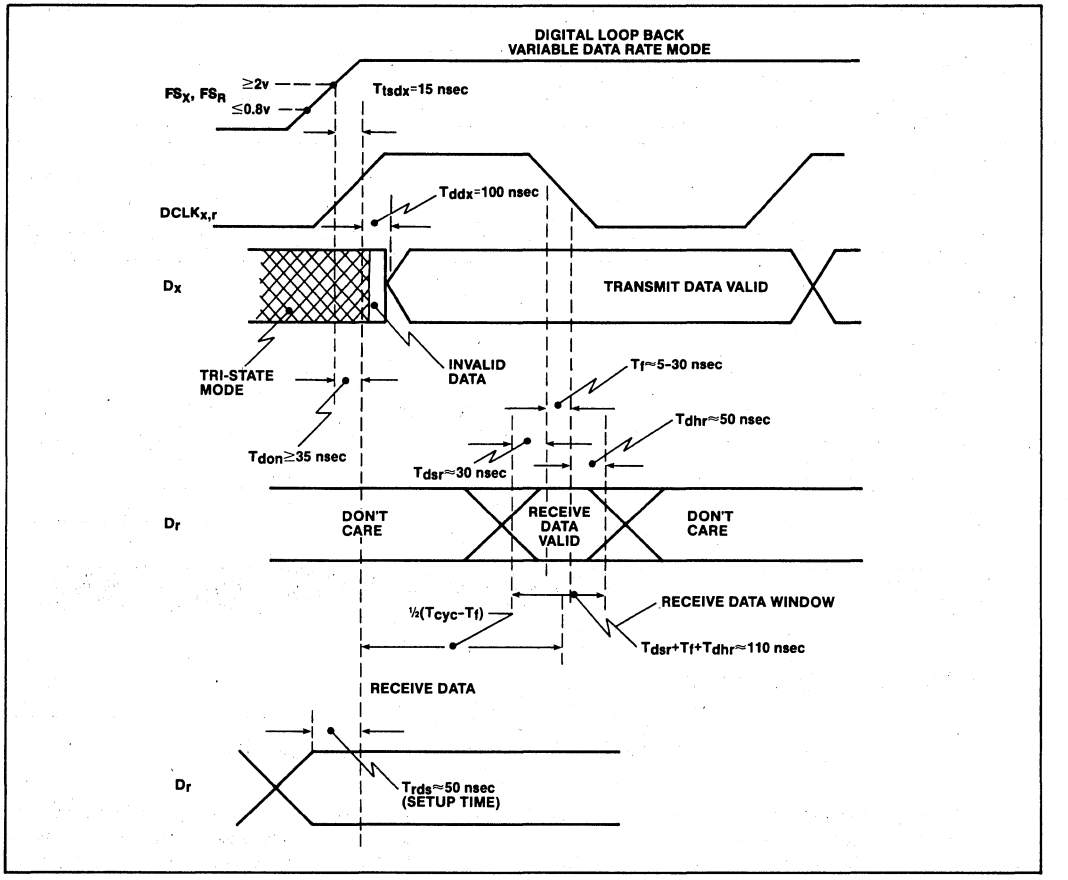


Figure 11. Waveform Timing Diagrams for the 2913/14

3.3 On-Line Test Modes

Two modes are available which permit maintenance checking of the linecard up to the SLIC/combochip interface, including the PCM highways and time slot interchanges. Tests include time slot-dependent error checking. The two test modes are called "redundancy testing" and "analog loopback." These test modes are described in detail in section 4.3.

4.0 MULTIMODE TEST CAPABILITIES

The 2913/14 was designed with every phase of design, manufacturing, and operation taken into consideration. In particular, several test modes have been implemented within the device with essentially no increase in the package size or pin count. These test modes fall into three categories: design/prototype tests, manufacturing tests, and on-line operation tests; see Table 8.

4.1 Design/Prototype Testing

In the design of a linecard prototype or in the qualification of a device, it is often helpful to have direct access to the internal nodes at key points in the LSI system. Some manufacturers even dedicate pins specifically for this function. The Intel 2913/14 approach was to reduce cost by using multifunction pins and smaller packages to achieve

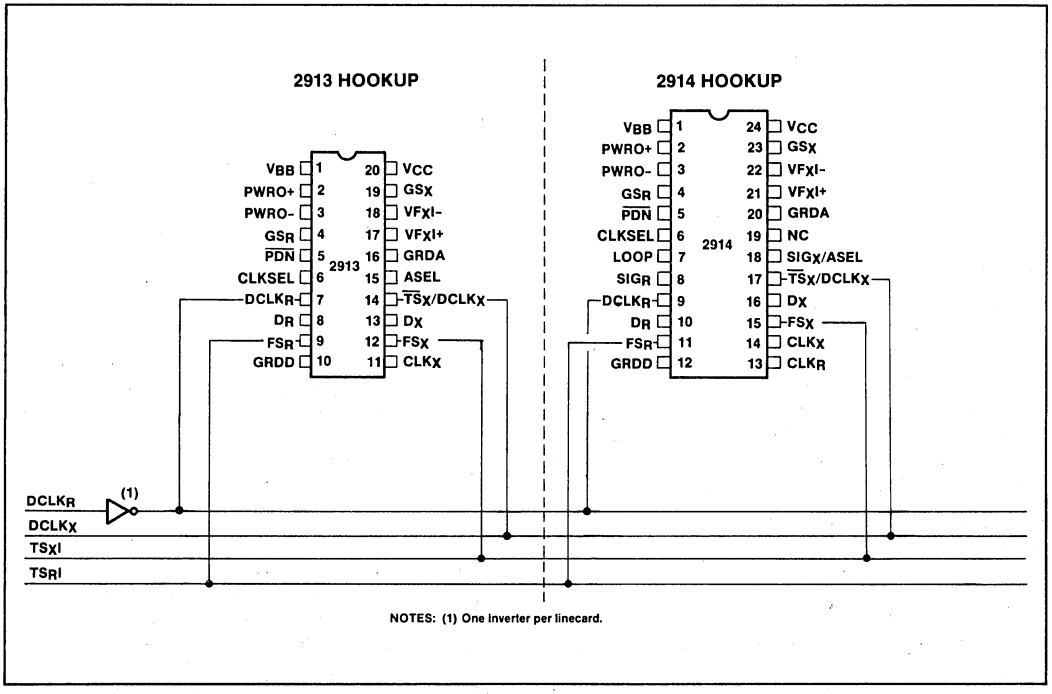


Figure 12. Circuit Diagram Showing Connections Needed to Retrofit the 2913/14 into Existing Variable Data Rate Systems

Table 8. Multimode Testing for Each Level from Design to On-Line Operation

- Design/Prototype Testing
  - —Direct access to transmit codec inputs
  - —Direct access to the receive filter input and the transmit filter differential outputs
- Manufacturing Tests
  - —Standard half channel tests for combined codec/filters
  - —Filter response half channel measurements
- Operation On-Line Tests
  - —Analog loopback for testing PCM and codec analog highways
  - —Redundancy checks with repeatable D_X outputs

this goal. Measurements through these multipurpose pins will typically yield full device capability against performance specifications, however *these measurements are not included in the device specifications.* This is done for two reasons: first, to save manufacturing cost by eliminating unnecessary tests and specifications, and, second, more cost effective manufacturing test techniques are available, as discussed in section 4.2.

Table 9 gives the input control pin values and the corresponding functions assigned to the key test pins on the 2914 for the design test modes.

Transmit Codec (Encoder)—The transmit filter can be bypassed by directly accessing the differential input of the transmit encoder with an analog differential drive signal. Table 9 shows the control pin voltages and the input pins for this test. This test mode permits DC testing of the encoder which is otherwise blocked by the AC coupling (low frequency reject filter) of the transmit filter.

Transmit and Receive Filter—Table 9 shows the control values that permit access to the differential outputs of the transmit filter and the single-ended input to the receive filter. The voltage difference between the transmit filter outputs represents the filtered output that will be

Table 9. 2914 Test Functions and Control Inputs for the Design Test Modes

Input		Pin Function (24-Pin Ver.)			Test Function
$\overline{PDN}$	DR	Pin 9 $DCLK_R$	Pin 17 $TSX/DCLKX$	Pin 18 $SIGX/ASEL$	
O-V_{CC}	O-V_{CC}	DCLKR	TSX/DCLKX	SIGX/ASEL	Normal Operation
V_{BB}	O-V_{CC}	—	+VFX	-VFX	Encoder
O-V_{CC}	V_{BB}	VFRI	+VFX0	-VFX0	RCV, XMIT Filter

Note: The terms used above are defined as:
±VFX = Encoder Input
±VFX0 = XMIT Filter Output
VFRI = RCV Filter Input

encoded. By driving VF_XI (single ended or differentially), the transmit filter response is obtained as a differential output. The final stage is the 60 Hz reject filter which is a switched capacitor filter sampled at an 8 kHz rate. When measured *digitally* (after the encoder), the filter characteristic is obtained directly; however, when measured in analog, a $\sin\left(\frac{\omega T}{2}\right)\Big/\frac{\omega T}{2}$ correction factor must be included.

The input to the receive filter first passes through a sample and hold. This is necessary to simulate the $\sin\left(\frac{\omega T}{2}\right)\Big/\frac{\omega T}{2}$ characteristic that results from the decoder D/A output. The net result is a filter characteristic that can be compared directly to the specifications.

Start-up Procedure for Test Modes—To place the 2913/14 in the test mode it is first necessary to operate the device for a few msec in normal operation. Then V_{BB} can be applied to the control pins to select the desired test access.

4.2 Production Testing

While it may be convenient for the designer to have access to both the filter and the codec inputs and outputs during the design or evaluation phase, the final product will always use the filter and codec circuits together with all signals passing through both on the way to or from the PCM highways. It therefore makes sense to perform all manufacturing measurements with the device configured in its normal operating mode, i.e., all measurements should be complete filter/codec half channel measurements. This approach not only tests the combo as it will actually be used, but also saves time and money by eliminating separate measurements and correlation exercises to determine the full half channel performance.

Since the transmission specifications of S/D, gain tracking, and ICN all require measurements which are "in-band" or "filter independent," the codec functions can be easily tested using conventional half channel measurement equipment. The apparent difficulty arises in trying to fully measure the filter characteristics beyond the half sampling frequency of 4 kHz. In fact, this is not really a problem with today's computer-based testing plus an understanding of the sampled data process which is discussed below under "Filter Testing."

ENCODER/DECODER TESTING

Transmission specifications are AC-coupled in-band measurements when using either CCITT G.712.11 methods 1 & 2 (white noise testing and sinusoidal testing, respectively) or AT&T Pub 43801 (Sinusoidal Testing). The noise testing uses a narrowband of flat noise from 300 to 500 Hz to drive the filter/codec (either in analog or the equivalent digital sequence for the transmit/receive channels, respectively). The resulting harmonic products are used to determine S/D. Likewise, gain tracking is also determined from this signal input. Sinusoidal testing uses a tone at 1.020 kHz for S/D measurements and gain tracking measurements. Idle channel noise measurements require the combined filter/codec since it has long been shown that separate measurements of filters and codecs are difficult to relate to the combined measurement (usually there is no specific relationship because of the non-linear properties of the encoder/decoder operations). Typically the frequency response of ICN measurements is primarily determined by the weighting filter (either C message or psophometric, which are both AC-coupled, bandpass type filters).

The conclusion is that combined filter/codec testing in no way limits the measurement of half channel transmission parameters of S/D, G.T., or ICN.

FILTER TESTING

Testing the filter response, of the transmit and receive channels presents two separate test situations which, in some ways, are mirror images of one another. With the transmit side, signals may be introduced at any frequency to test the filter response. At the output of the filter, the resulting signals are sampled at 8 kHz and digitized resulting in a sequence of PCM words representing the

samples of the filtered input signal. On the receive side, a digital PCM sequence of samples representing the driving signal is converted to an analog signal by the decoder and can be measured at the filter output in analog form.

Sampling Process—In both cases of testing the filter, the signal eventually is in a sampled form. Since the sampling rate is fixed at 8 kHz, all signals must be represented below 4 kHz (half the sampling frequency). This means that the PCM bit stream can only represent signals at frequencies below 4 kHz. If a signal above 4 kHz is sampled, those samples appear exactly as if the signal was at a frequency mirror imaged about 4 kHz. Two examples include signals at 5 kHz and 7 kHz which will result in samples that look like signals of 5 – 8 kHz = 3 kHz and 7 – 8 kHz = 1 kHz, respectively.

Conversely, the sampling process produces replicas (aliasing) of the sampled signal around multiples of the sampling frequency. Therefore, if two signals are introduced digitally representing 1 kHz and 2 kHz, there will also be frequency components located at 8 kHz = ±1 kHz and 8 kHz = ±2 kHz, and so on for all multiples of 8 kHz. Thus it is possible to generate frequencies at arbitrary values after sampling by controlling the frequency of each signal within the 4 kHz input band regardless of whether it is in analog or PCM.

When an analog signal is sampled, the frequency components generated are all of the same amplitude as the corresponding input spectral components. Therefore, on the transmit side, measurements made from the PCM data will have a throughput gain of unity except where components are superimposed (e.g., a 4 kHz input signal will have an alias component at 4 kHz which may double the amplitude at 4 kHz when the two components are combined).

When an analog signal is reconstructed from digital samples, it goes through a sample and hold stage which has the effect of imposing a weighting function on the resulting spectral components that is represented by

$$\text{Sinc}\left[\frac{\omega T}{2}\right] = \frac{\text{Sin}\left(\frac{\omega T}{2}\right)}{\frac{\omega T}{2}}$$

where ω is the actual spectral component frequency going into the filter, and T is the width of the hold pulse at the decoder output. For the 2913/14, the analog output is held the full sample period of 125 μsec (1/8000 Hz) so that a frequency component at f_t will have a weighting of

$$W = \left(\frac{8000}{\pi f_t}\right) \text{Sin}\left[\frac{\pi f_t}{8000}\right]$$

Transmit Filter Test Approach—Two approaches can be used for half channel testing of the transmit filter characteristic: (1) input analog test frequencies and perform an FFT on the corresponding PCM samples that are generated to determine spectral frequencies and amplitudes at the codec output, or (2) use an "ideal" D/A converter on the PCM samples to convert the digital data back to analog so that the spectral amplitudes and frequencies can be determined using analog circuits such as spectrum analyzers or filter banks. In either case, the effects of sampling will be the same. Figure 13 shows two spectral diagrams of amplitude versus frequency. The top diagram represents the locations of nine test frequencies corresponding to the seven specified frequencies in the 2913/14 data sheet plus a component at 7 kHz and one at 10 kHz. The bottom figure shows the "equivalent" spectral component locations when carried in the PCM bit stream. As an example, frequency #8 is located at 7 kHz. The corresponding PCM frequency is seen in the lower figure at 1 kHz. Note also that the analog component at 9 kHz (see #8*) would also generate the 1 kHz component in the PCM data.

To test the filter, the desired test frequencies are introduced in analog to the filter input in such a way that there is no confusion as to where the resulting component will be after sampling (i.e., don't simultaneously put in 1 kHz and 7 kHz since both of these inputs result in a 1 kHz component in the PCM data). Then, using either technique (FFT or analog) mentioned above, measure the amplitude of the corresponding sampled component. The

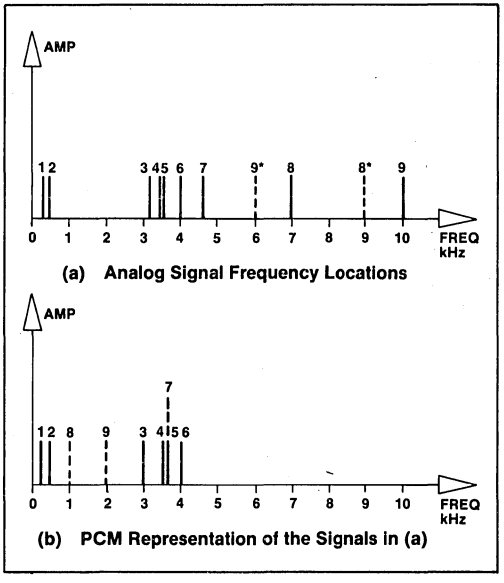


Figure 13. Spectral Properties of the Filter Test Frequencies in Analog and PCM

difference between that amplitude and the input amplitude represents the filter attenuation *at the frequency of the input signal.* So, if the input signal was at 7 kHz, the FFT will determine the amplitude of the corresponding 1 kHz signal. The amplitude change relative to the input will represent the filter attenuation at 7 kHz.

Receive Filter Test Approach—In this case, the PCM test signals can be generated directly from digital circuits or by going through an "ideal" A/D (companded) to generate the PCM samples. Since these samples represent frequencies below the half sampling rate, Figure 12(b) now represents the input signals and 12(a) the output, but with one significant difference—a Sinc[π f_I/8000] weighting function is imposed on all the frequency components because of the decoder sample and hold output. At the filter output, the spectral component amplitudes will include the effect of the filter response *and* the weighting function measured at the actual test frequency. The receive filter includes a compensation network for the weighting function in its passband. Therefore, inside the passband (300 Hz to 3.4 kHz) the measured amplitudes should be compared directly to the data sheet specifications. Frequencies outside the passband must be compensated for the weighting function first to determine the true filter response.

Summary of Filter Testing—Table 10 lists the nine test frequencies shown in Figure 12 for both the transmit and receive filter testing. For each filter test, the input frequency (analog or PCM), measurement frequency, and test circuit gain is tabulated corresponding to the desired test frequency. The various weighting values are easily handled by computer-based test equipment since the inverse weighting function can be stored in the computer and applied to each measured amplitude as appropriate.

4.3 Operational On-Line Testing

Two test modes are available which facilitate on-line testing to verify operation of both the combochip and the entire switching highway network. The first is simply the capability to duplicate the same D_X transmission in multiple PCM time slots (redundancy checking), and the second is the analog loopback capability which allows the testing of a call completion through the entire PCM voice path including the time slot interchange network.

Redundancy Checking—A feature of the 2913/14 is that the same 8-bit PCM word can be put on the D_X highway in multiple time slots simply by holding the frame sync/data enable (FS_X) high and continuing to supply clock pulses (CLK_X or $DCLK_X$). If the data enable was held high for multiple time slots, each time slot would have identical data in it. By routing this data through the PCM highways, time slot interchanges, etc., and then correlating the data between time slots, it would be possible to detect time slot-dependent data errors. When this test mode is used, no other data will be generated for the transmit highway until the frame sync returns low for at least one full clock cycle.

Analog Loopback—The 2914 (2913 does not have this feature) has the capability to be remotely programmed to disconnect the outside telephone lines and tie the transmit input directly to the receive output to effect analog loopback within the combo chip. This is accomplished by setting the LOOP input to V_{CC} (TTL high). The result is to disconnect VF_XI+ and VF_XI- from the external circuitry and to connect internally PWRO+ to VF_XI+, GS_r to PWRO–, and VF_XI- to GS_X (see Figure 14).

With this test set up, the entire PCM and analog trans-

Table 10. Filter Response Testing Input/Output Frequencies and Amplitude Gain Schedule

		Transmit			Receive		
	Test Freq.	Input Freq.	Measured Freq.	Amp Weighting	Input Freq.	Measured Freq.	Amp Weighting
1	200	200	200	1	200	200	1
2	300	300	300	1	300	300	1
3	3000	3000	3000	1	3000	3000	1
4	3300	3300	3300	1	3300	3300	1
5	3400	3400	3400	1	3400	3400	1
6	4000	4000	4000	0 to 2	4000	4000	0 to 2
7	4600	4600	3400	1	3400	4600	$\text{Sinc}\left[\frac{4600\,\pi}{8000}\right]$
8	7000	7000	1000	1	1000	7000	$\text{Sinc}\left[\frac{7000\,\pi}{8000}\right]$
9	10000	10000	2000	1	2000	10000	$\text{Sinc}\left[\frac{10000\,\pi}{8000}\right]$

mission path up to the SLIC can be tested remotely by assigning a PCM word to a time slot that is read by the combo being tested. This data is converted to analog and passed out of the receive channel. It is taken as input by the transmit channel where it is filtered and re-digitized (encoded) back to PCM. The PCM word can now be put on the transmit highway and sent back to the remote test facility. By comparing the PCM data (individually or as a series of codes) the health of that particular connection can be verified.

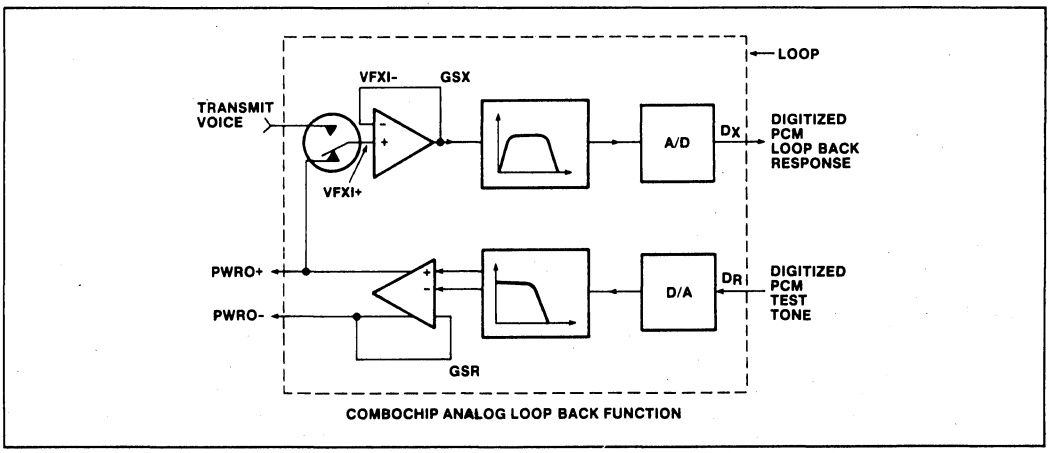


Figure 14. Simplified Block Diagram of 2914 Combochip in the Analog Loopback Configuration